IEC 60384-21-1

(First edition - 2004-06)

Fixed capacitors for use in electronic equipment -

Part 21-1: Blank detail specification: Fixed surface mount multilayer capacitors

of ceramic dielectric, Class 1 - Assessment level EZ

CORRIGENDUM 1

Page 6

INTRODUCTION

Replace, in the last row of the table, the reference IECQ 001005 by IEC QC 001005.

Page 7

Table 2 – Values of capacitance and of voltage related to case sizes

Replace, in the third row of the first column 'Rated capacitance (in pF, nF)' by 'Rated capacitance (in pF and/or nF)'.

Page 8

1.4 Normative references

Add, to the list, the title of the following standard:

IEC 60410:1973, Sampling plans and procedures for inspection by attributes

Page 8

1.6 Ordering information

Replace, in item c), 'DC' by 'd.c.'.

Page 11

Table 4 – Test schedule for quality conformance inspection

Replace the existing text of page 11 by the following:

Table 4 – Test schedule for quality conformance inspection (continued)

Subclause number and test ¹⁾		D or ND	Conditions of test 1)	Number of specimens and number of non- conformances ²⁾			Performance requirements 1)
				p	n	c	
Group C inspection							
(periodic)							
Subgroup C1		D		3	12	0	
4.15	Robustness of termination (if required)		Test Ua1, Force: 2,5 N Test Ub, Method 1, Force: 2,5 N Number of bends:1 Visual examination				No visible damage
4.9.1	Initial measurement		Capacitance				damage
4.9	Resistance to soldering heat		See detail specification for the method				
4.9.4	Final measurements		Visual examination Capacitance				As in 4.9.4 As in 4.9.4
4.16	Component solvent resistance (if required)		Solvent: Solvent temperature: Method 2 Recovery:				See detail specification
Subgroup C2		D		3	12	0	
4.8	Substrate bending test		Deflection: Number of bends:			8)	See detail specification
4.8.1 Initial measurement			Capacitance				
4.8.2	Final inspection		Capacitance (with printed board in bent position)				<i>ΔC/C</i> ≤ 5%
			Visual examination				No visible damage